

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Atty. Docket

FRIEDRICH HAPKE

DE 010056

Serial No.

Group Art Unit

Filed: CONCURRENTLY

Ex.

Title: ARRANGEMENT AND METHOD FOR TESTING INTEGRATED CIRCUITS

Commissioner for Patents  
Washington, D.C. 20231

#5  
pre/amend-A  
T.B.  
9/4/02

PRELIMINARY AMENDMENT

Sir:

Prior to calculation of the filing fee and examination, please  
amend the above-identified application as follows:

IN THE CLAIMS

Please amend claim 5 as follows:

5. (amended) The arrangement as claimed in claim 3, wherein a  
test pattern counter (14; 28) is provided which counts a clock  
signal and supplies the counting result to the bit flipping  
controller (6; 27) and/or the masking logic circuit (13; 29).

REMARKS

The foregoing amendments to the claims were made solely to